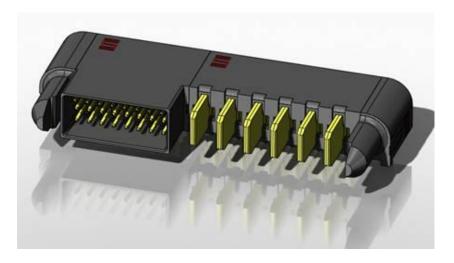
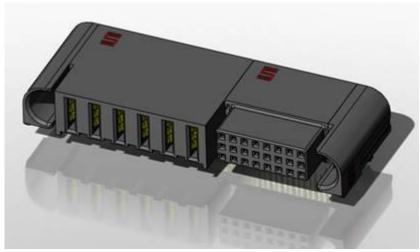


Project Number: 220319	Tracking Code: 220319_Report_Rev_2	
Requested by: Steven Xu	Date: 5/20/2013	
Part #: ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP	Tech: Kason He Eng: Vico Zhao	
Part description: ET60S/ET60T	Qty to test: 50	
Test Start: 10/22/2012	Test Completed: 12/2/2012	





DESIGN QUALIFICATION TEST REPORT

ET60S/ET60T ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP

Tracking Code: 220319_Report_Rev_2	Part #: ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP			
Part description: FT60S/FT60T				

REVISION HISTORY

DATA	REV.NUM.	DESCRIPTION	ENG
1/4/2013	1	Initial Issue	КН
5/20/2013	2	Insert additional CCC graph	CE

Tracking Code: 220319_Report_Rev_2	Part #: ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP
Part description: ET60S/ET60T	

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Samtec Test PCBs used: PCB-103705-TST/PCB-103706-TST//PCB-103697-TST PCB-103818-TST/PCB-103819-TST

FLOWCHARTS

Gas Tight

TEST	GROUP A1	
STEP	192 Points	
01	LLCR-1	
02	Gas Tight	
03	LLCR-2	

Gas Tight = EIA-364-36A

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

Max delta allowed is 20 mOhms

Normal Force

TEST	GROUP A1	GROUP A2	GROUP B1	GROUP B2
STEP	Individual Contacts (8-10 min)	Individual Contacts (8-10 min)	Power - Individual Contacts (8-10 min)	Power - Individual Contacts (8-10 min)
01	Contact Gaps	Contact Gaps	Contact Gaps	Contact Gaps
02	Setup Approved	Thermal Aging (Mated and Undisturbed)	Setup Approved	Thermal Aging (Mated and Undisturbed)
03	Normal Force (in the body and soldered on PCB unless otherwise specified)	Contact Gaps	Normal Force (in the body and soldered on PCB unless otherwise specified)	Contact Gaps
04		Setup Approved		Setup Approved
05		Normal Force (in the body and soldered on PCB unless otherwise specified)		Normal Force (in the body and soldered on PCB unless otherwise specified)

Thermal Aging = EIA-364-17, Test Condition 4 (105°C)

Time Condition 'B' (250 Hours)

Normal Force = EIA-364-04

(Perpendicular) Displacement Force = 12.7 mm/min ± 6 mm/min

Spec is 50 N @ 1 mm displacement

Contact Gaps / Height - No standard method. Usually measured optically

Gaps to be taken on a minimum of 20% of each part tested

Test all beams from each contact

Signal = 2 beams per x 3 contacts

Power = 3 beams per

Part description: ET60S/ET60T

FLOWCHARTS Continued

Thermal Aging

TEST	GROUP A1		
STEP	8 Boards		
	Thermal Aging (Mated)		
01	Contact Gaps		
02	Forces - Mating / Unmating		
03	LLCR-1		
04	Thermal Aging (Mated and Undisturbed)		
05	LLCR-2		
06	Forces - Mating / Unmating		
07	Contact Gaps		

Thermal Aging = EIA-364-17, Test Condition 4 (105°C)

Time Condition 'B' (250 Hours)

Mating / Unmating Forces = EIA-364-13

Contact Gaps / Height - No standard method. Usually measured optically.

Gaps to be taken on a minimum of 20% of each part tested

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

Part description: ET60S/ET60T

FLOWCHARTS Continued

Durability/Mating/Unmating/Gaps

TEST	GROUP B1		
STEP	8 Boards		
SIEP	(largest position submitted)		
01	Contact Gaps		
02	LLCR-1		
03	Forces - Mating / Unmating		
04	25 Cycles		
05	Forces - Mating / Unmating		
06	25 Cycles (50 Total)		
07	Forces - Mating / Unmating		
80	25 Cycles (75 Total)		
09	Forces - Mating / Unmating		
10	25 Cycles (100 Total)		
11	Forces - Mating / Unmating		
12	Clean w/Compressed Air		
13	Contact Gaps		
14	LLCR-2		
15	Thermal Shock		
	(Mated and Undisturbed)		
16	LLCR-3		
17	Cyclic Humidity		
	(Mated and Undisturbed)		
18	LLCR-4		
19	Forces - Mating / Unmating		

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25°C to +65°C @ 90% RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

Mating / Unmating Forces = EIA-364-13

Contact Gaps / Height - No standard method. Usually measured optically.

Gaps to be taken on a minimum of 20% of each part tested

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

Part description: ET60S/ET60T

FLOWCHARTS Continued

IR & DWV

TEST	GROUP A1	GROUP A2	GROUP A3	GROUP B1
STEP	2 Mated Sets	2 Unmated of Part # Being Tested	2 Unmated of Mating Part #	2 Mated Sets
	Break Down Pin-to-Pin	Break Down Pin-to-Pin	Break Down Pin-to-Pin	Pin-to-Pin
01	DWV/Break Down Voltage	DWV/Break Down Voltage	DWV/Break Down Voltage	IR & DWV at test voltage (on both mated sets and on each connector unmated)
02				Thermal Shock (Mated and Undisturbed)
03				IR & DWV at test voltage (on both mated sets and on each connector unmated)
04				Cyclic Humidity (Mated and Undisturbed)
05				IR & DWV at test voltage (on both mated sets and on each connector unmated)

DWV on Group B1 to be performed at Test Voltage

DWV test voltage is equal to 75% of the lowest break down voltage from Groups A1, A2 or A3

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25°C to +65°C @ 90% RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

IR = EIA-364-21

DWV = EIA-364-20, Test Condition 1

Part description: ET60S/ET60T

FLOWCHARTS Continued

TEST	GROUP C1	GROUP C2	GROUP C3	GROUP D1
STEP	2 Mated Sets	2 Unmated of Part # Being Tested	2 Unmated of Mating Part #	2 Mated Sets
	Break Down Row-to-Row	Break Down Row-to-Row	Break Down Row-to-Row	Row-to-Row
01	DWV/Break Down Voltage	DWV/Break Down Voltage	DWV/Break Down Voltage	IR & DWV at test voltage (on both mated sets and on each connector unmated)
02				Thermal Shock (Mated and Undisturbed)
03				IR & DWV at test voltage (on both mated sets and on each connector unmated)
04				Cyclic Humidity (Mated and Undisturbed)
05				IR & DWV at test voltage (on both mated sets and on each connector unmated)

TEST	GROUP E1	GROUP E2	GROUP E3	GROUP F1
STEP	2 Mated Sets	2 Unmated of Part # Being Tested	2 Unmated of Mating Part #	2 Mated Sets
	Break Down Pin-to-Power	Break Down Pin-to-Power	Break Down Pin-to-Power	Pin-to-Power
01	DWV/Break Down Voltage	DWV/Break Down Voltage	DWV/Break Down Voltage	IR & DWV at test voltage (on both mated sets and on each connector unmated)
02				Thermal Shock (Mated and Undisturbed)
03				IR & DWV at test voltage (on both mated sets and on each connector unmated)
04				Cyclic Humidity (Mated and Undisturbed)
05				IR & DWV at test voltage (on both mated sets and on each connector unmated)

Tracking Code: 220319_Report_Rev_2 Part #: ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP

Part description: ET60S/ET60T

FLOWCHARTS Continued

TEST	GROUP G1	GROUP G2	GROUP G3	GROUP H1
STEP	2 Mated Sets	2 Unmated of Part # Being Tested	2 Unmated of Mating Part #	2 Mated Sets
	Break Down Power-to-Power	Break Down Power-to-Power	Break Down Power-to-Power	Power-to-Power
01	DWV/Break Down Voltage	DWV/Break Down Voltage	DWV/Break Down Voltage	IR & DWV at test voltage (on both mated sets and on each connector unmated)
02				Thermal Shock (Mated and Undisturbed)
03				IR & DWV at test voltage (on both mated sets and on each connector unmated)
04				Cyclic Humidity (Mated and Undisturbed)
05				IR & DWV at test voltage (on both mated sets and on each connector unmated)

Tracking Code: 220319_Report_Rev_2 Part #: ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP

Part description: ET60S/ET60T

FLOWCHARTS Continued

POWER PINS

Current Carrying Capacity - Power Pins

TEST	GROUP A1	GROUP A2	GROUP A3	GROUP A4	GROUP A5
STEP	3 Mated Assemblies				
				_	
	1 Contact Powered	2 Contacts Powered	3 Contacts Powered	4 Contacts Powered	All Contacts Powered

SIGNAL PINS

Current Carrying Capacity - Singal Pins

TEST	GROUP D1	GROUP D2	GROUP D3	GROUP D4	GROUP D5
STEP	3 Mated Assemblies	3 Mated Assemblies	3 Mated Assemblies	3 Mated Assemblies	3 Mated Assemblies
	1 Vertical Row	2 Adjacent Vertical	3 Adjacent Vertical	4 Adjacent Vertical	All Contacts Powered
	Powered	Rows Powered	Rows Powered	Rows Powered	

POWER & SIGNAL PINS

Current Carrying Capacity - Power and Signal Pins

TEST	GROUP E1
STEP	3 Mated Assemblies
	Signal Pins @ 1/2 rated current from
	Group D5
	Power Pins - All Contacts Powered
01	CCC

(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C (GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C CCC, Temp rise = EIA-364-70

Part description: ET60S/ET60T

FLOWCHARTS Continued

Mechanical Shock / Vibration / LLCR

TEST	GROUP A1
STEP	192 Points
01	LLCR-1
02	Shock
03	Vibration
04	LLCR-2

Mechanical Shock = EIA 364-27 Half Sine,

100 g's, 6 milliSeconds (Condition "C") each axis

Vibration = EIA 364-28, Random Vibration

7.56 g RMS, Condition VB --- 2 hours/axis

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

Max delta allowed is 20 mOhms

Shock / Vibration / nanoSecond Event Detection

TEST	GROUP A1
STEP	60 Points
01	Event Detection, Shock
02	Event Detection, Vibration

Mechanical Shock = EIA 364-27 Half Sine,

100 g's, 6 milliSeconds (Condition "C") each axis

Vibration = EIA 364-28, Random Vibration

7.56 g RMS, Condition VB --- 2 hours/axis

Event detection requirement during Shock / Vibration is 50 nanoseconds minimum

Part description: ET60S/ET60T

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL SHOCK:

- 1) EIA-364-32, Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

THERMAL:

- 1) EIA-364-17, Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors.
- 2) Test Condition 4 at 105° C.
- 3) Test Time Condition B for 250 hours.
- 4) All test samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

- 1) Reference document: EIA-364-31, Humidity Test Procedure for Electrical Connectors.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

MECHANICAL SHOCK (Specified Pulse):

- 1) Reference document: EIA-364-27, Mechanical Shock Test Procedure for Electrical Connectors
- 2) Test Condition C
- 3) Peak Value: 100 G
- 4) Duration: 6 Milliseconds
- 5) Wave Form: Half Sine
- 6) Velocity: 12.3 ft/s
- 7) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

VIBRATION:

- 1) Reference document: EIA-364-28, Vibration Test Procedure for Electrical Connectors
- 2) Test Condition V, Letter B
- 3) Power Spectral Density: 0.04 G² / Hz
- 4) G'RMS': 7.56
- 5) Frequency: 50 to 2000 Hz
- 6) Duration: 2.0 Hours per axis (3 axis total)

NANOSECOND-EVENT DETECTION:

- 1) Reference document: EIA-364-87, Nanosecond-Event Detection for Electrical Connectors
- 2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
- 3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

MATING/UNMATING:

- 1) Reference document: EIA-364-13, Mating and Unmating Forces Test Procedure for Electrical Connectors.
- 2) The full insertion position was to within 0.003" to 0.004" of the plug bottoming out in the receptacle to prevent damage to the system under test.
- 3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):

- 1) Reference document: EIA-364-04, Normal Force Test Procedure for Electrical Connectors.
- 2) The contacts shall be tested in the connector housing.
- 3) If necessary, a "window" shall be made in the connector body to allow a probe to engage and deflect the contact at the same attitude and distance (plus 0.05 mm [0.002"]) as would occur in actual use.
- 4) The connector housing shall be placed in a holding fixture that does not interfere with or otherwise influence the contact force or deflection.
- 5) Said holding fixture shall be mounted on a floating, adjustable, X-Y table on the base of the Dillon TC², computer controlled test stand with a deflection measurement system accuracy of 5.0 μm (0.0002").
- 6) The nominal deflection rate shall be 5 mm (0.2")/minute.
- 7) Unless otherwise noted a minimum of five contacts shall be tested.
- 8) The force/deflection characteristic to load and unload each contact shall be repeated five times.
- 9) The system shall utilize the TC^2 software in order to acquire and record the test data.
- 10) The permanent set of each contact shall be measured within the TC² software.
- 11) The acquired data shall be graphed with the deflection data on the X-axis and the force data on the Y-axis and a print out will be stored with the Tracking Code paperwork.

NORMAL FORCE (FOR CONTACTS TESTED OUTSIDE THE HOUSING):

- 1) Reference document: EIA-364-04, Normal Force Test Procedure for Electrical Connectors.
- 2) The contacts shall be tested in the loose state, *not* inserted in connector housing.
- 3) The contacts shall be prepared to allow access to the spring member at the same attitude and deflection level as would occur in actual use.
- 4) In the event that portions of the contact prevent insertion of the test probe and/or deflection of the spring member under evaluation, said material shall be removed leaving the appropriate contact surfaces exposed.
- 5) In the case of multi-tine contacts, each tine shall be tested independently on separate samples as required.
- 6) The connector housing shall be simulated, if required, in order to provide an accurate representation of the actual contact system performance.
- 7) A holding fixture shall be fashioned to allow the contact to be properly deflected.
- 8) Said holding fixture shall be mounted on a floating, adjustable, X-Y table on the base of the Dillon TC^2 , computer controlled test stand with a deflection measurement system accuracy of 5 μ m (0.0002").
- 9) The probe shall be attached to a Dillon P/N 49761-0105, 5 N (1.1 Lb) load cell providing an accuracy of \pm 0.2%.
- 10) The nominal deflection rate shall be 5 mm (0.2")/minute.
- 11) Unless otherwise noted a minimum of five contacts shall be tested.
- 12) The force/deflection characteristic to load and unload each contact shall be repeated five times.
- 13) The system shall utilize the TC² software in order to acquire and record the test data.
- 14) The permanent set of each contact shall be measured within the TC² software.
- 15) The acquired data shall be graphed with the deflection data on the X-axis and the force data on the Y-axis and a print out will be stored with the Tracking Code paperwork.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) EIA-364-70, Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets.
- 2) When current passes through a contact, the temperature of the contact increases as a result of I^2R (resistive) heating.
- 3) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
- 4) The size of the temperature probe can affect the measured temperature.
- 5) Copper traces on PC boards will contribute to temperature rise:
 - a. Self heating (resistive)
 - b. Reduction in heat sink capacity affecting the heated contacts
- 6) A de-rating curve, usually 20%, is calculated.
- 7) Calculated de-rated currents at three temperature points are reported:
 - a. Ambient
 - b. 80° C
 - c. 95° C
 - d. 115° C
- 8) Typically, neighboring contacts (in close proximity to maximize heat build up) are energized.
- 9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the maximum temperature in the vicinity of the heat generation area.
- 10) A computer program, TR 803.exe, ensures accurate stability for data acquisition.
- 11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
- 12) Hook-up wire length is longer than the minimum specified in the referencing standard.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

LLCR:

- 1) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. <= +5.0 mOhms: -----Stable
 - b. +5.1 to +10.0 mOhms:-----Minor
 - c. +10.1 to +15.0 mOhms: ------Acceptable
 - d. +15.1 to +50.0 mOhms: ------Marginal
 - e. +50.1 to +2000 mOhms: ------Unstable
 - f. >+2000 mOhms:-----Open Failure

GAS TIGHT:

To provide method for evaluating the ability of the contacting surfaces in preventing penetration of harsh vapors which might lead to oxide formation that may degrade the electrical performance of the contact system.

- 1) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. <= +5.0 mOhms:-----Stable
 - b. +5.1 to +10.0 mOhms: ------Minor
 - c. +10.1 to +15.0 mOhms: ------Acceptable
 - d. +15.1 to +50.0 mOhms: ------Marginal
 - e. +50.1 to +2000 mOhms:-----Unstable
 - f. >+2000 mOhms: -----Open Failure
- 4) Procedure:
 - a. Reference document: EIA-364-36, Test Procedure for Determination of Gas-Tight Characteristics for Electrical Connectors, Sockets and/or Contact Systems.
 - b. Test Conditions:
 - i. Class II--- Mated pairs of contacts assembled to their plastic housings.
 - ii. Reagent grade Nitric Acid shall be used of sufficient volume to saturate the test chamber
 - iii. The ratio of the volume of the test chamber to the surface area of the acid shall be 10:1.
 - iv. The chamber shall be saturated with the vapor for at least 15 minutes before samples are added.
 - v. Exposure time, 55 to 65 minutes.
 - vi. The samples shall be no closer to the chamber walls than 1 inches and no closer to the surface of the acid than 3 inches.
 - vii. The samples shall be dried after exposure for a minimum of 1 hour.
 - viii. Drying temperature 50° C
 - ix. The final LLCR shall be conducted within 1 hour after drying.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

INSULATION RESISTANCE (IR):

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-21, Insulation Resistance Test Procedure for Electrical Connectors.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Electrification Time 2.0 minutes
 - iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
- 2) MEASUREMENTS:
- 3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 5000 megohms.

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-20, Withstanding Voltage Test Procedure for Electrical Connectors.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Barometric Test Condition 1
 - iii. Rate of Application 500 V/Sec
 - iv. Test Voltage (VAC) until breakdown occurs
- 2) MEASUREMENTS/CALCULATIONS
 - a. The breakdown voltage shall be measured and recorded.
 - b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
 - c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

Part description: ET60S/ET60T

RESULTS

Temperature Rise, CCC at a 20% de-rating

Power pin

- CCC for a 30°C Temperature Rise-----70.0A per contact with 1 adjacent power contacts powered
- CCC for a 30°C Temperature Rise-----59.5A per contact with 2 adjacent power contacts powered
- CCC for a 30°C Temperature Rise-----52.8A per contact with 3 adjacent power contacts powered
- CCC for a 30°C Temperature Rise------48.2A per contact with 4 adjacent power contacts powered
- CCC for a 30°C Temperature Rise-----45.0A per contact with all adjacent power contacts powered

Signal pin

- CCC for a 30°C Temperature Rise-----3.3A per contact with 3 adjacent signal contacts powered
- CCC for a 30°C Temperature Rise------2.5A per contact with 6 adjacent signal contacts powered
- CCC for a 30°C Temperature Rise-----2.2A per contact with 9 adjacent signal contacts powered
- CCC for a 30°C Temperature Rise-----2.0A per contact with 12 adjacent signal contacts powered
- CCC for a 30°C Temperature Rise------1.6A per contact with all adjacent signal contacts powered

Power pin and Signal pin

• CCC for a 30°C Temperature Rise------43.1A per contact with all adjacent power contacts powered and signal contacts powered @ 1/2 rated current @ .95 AMPS.

Mating/Unmating Forces: Thermal Aging Group

- Initial
 - Mating
 - Min ----- 6.52 Lbs
 - Max-----10.98 Lbs
 - Unmating
 - Min ----- 5.33 Lbs
 - Max----- 6.10 Lbs
- After Thermal
 - Mating
 - Min ----- 4.63 Lbs
 - Max----- 5.08 Lbs
 - Unmating
 - Min ----- 3.31 Lbs
 - Max------4.06 Lbs

RESULTS Continued

			RESCETS Continued
Matin		ating F	orces: Mating/Unmating Durability Group
•	Initial		
	0	Mating	
		•	Min 5.93 Lbs
		•	Max 7.70 Lbs
	0	Unmati	ng
		•	Min 4.98 Lbs
		•	Max 6.05 Lbs
•	After 2	5 Cycles	
	0	Mating	
	O	•	Min 7.25 Lbs
			Max8.71 Lbs
	0	Unmati	
	O		Min 5.78 Lbs
		-	Max7.17 Lbs
	A C4 5		Max/.1/ LDS
•		0 Cycles	
	0	Mating	200
		•	Min
		·	Max9.58 Lbs
	0	Unmati	
		•	Min 6.29 Lbs
		•	Max7.97 Lbs
•	After 7	5 Cycles	
	0	Mating	
		•	Min 8.98 Lbs
		•	Max10.94 Lbs
	0	Unmati	
		•	Min 7.15 Lbs
		•	Max 8.93 Lbs
•	After 1	00 Cycles	S
	0	Mating	
		•	Min 9.93 Lbs
		•	Max12.31 Lbs
	0	Unmati	
	-	•	Min 8.35 Lbs
			Max 9.96 Lbs
•	After F	Iumidity	70 200
•	Alter I	Mating	
	0	.viating	Min 4.83 Lbs
			Max6.25 Lbs
	0	- Unmati	
	O	omnati	Min 3.66 Lbs
		:	Max5.02 Lbs
		-	WIAX 5.02 LDS

RESULTS Continued Normal Force at 0.0132 inches deflection power pin Left **Initial** Min------442.10 gf Set ---- 0.0005 in Max ----- 503.90 gf Set ---- 0.0016 in 0 **Thermal** Min------264.60 gf Set----- 0.0043 in 0 Max ----- 334.20 gf Set----- 0.0053 in Middle Initial Min------420.80 gf Set ---- 0.0001 in Max ------498.90 gf Set ---- 0.0005 in 0 **Thermal** Min-----252.70 gf Set----- 0.0045 in 0 Max ------297.60 gf Set----- 0.0055 in Right Initial Min------401.00 gf Set ---- 0.0000 in Max ------ 472.50 gf Set ---- 0.0004 in \circ **Thermal** Min-----252.20 gf Set----- 0.0041 in Max ------295.10 gf Set----- 0.0051 in Normal Force at 0.009 inches deflection signal pin **Row1 Left** Initial Min------ 110.20 gf Set ---- 0.0000 in Max ----- 133.60 gf Set ---- 0.0005 in 0 Thermal Min------ 109.40 gf Set----- 0.0005 in Max ------ 129.00 gf Set----- 0.0016 in 0 Row1 right Initial Min------ 110.40 gf Set ---- 0.0001 in 0 Max ----- 134.40 gf Set ---- 0.0004 in **Thermal** Min------104.00 gf Set----- 0.0008 in Max ------ 131.90 gf Set----- 0.0020 in \circ **Row2 Left** Initial Min------ 115.50 gf Set ---- 0.0001 in Max ----- 131.90 gf 0 Set ---- 0.0003 in **Thermal** Min------ 103.90 gf Set----- 0.0006 in 0 Max ----- 130.50 gf Set----- 0.0012 in 0 Row2 right **Initial** Min------ 111.70 gf Set ---- 0.0001 in Max ------ 127.80 gf Set ---- 0.0004 in 0 **Thermal** Min----- 100.00 gf Set---- 0.0007 in 0 Max ------ 118.80 gf Set----- 0.0018 in

RESULTS Continued Normal Force at 0.009 inches deflection signal pin **Row3 Left** Initial Min------111.20 gf Set ---- 0.0000 in 0 Max ----- 134.40 gf Set ---- 0.0003 in 0 **Thermal** Min------ 109.40 gf Set----- 0.0007 in 0 Max ------ 124.90 gf Set----- 0.0012 in Row3 right Initial Min------ 110.00 gf Set ---- 0.0002 in Max ------ 122.70 gf Set ---- 0.0007 in 0 **Thermal** Min------ 102.00 gf Set----- 0.0007 in 0 Max ------ 128.00 gf Set----- 0.0015 in **Insulation Resistance minimums, IR** Pin to Pin Initial $Mated-------- 10000 Meg \ \Omega ------ Passed$ Unmated ------ Passed 0 **Thermal** Unmated ------ Passed 0 Humidity Mated ----- Passed Unmated ------ 6423Meg Ω ------ Passed Pin to Power Initial Unmated ------ Passed **Thermal** Unmated ------ Passed 0 Humidity Mated------ Passed 0 Unmated ------ Passed **Power to Power** Initial Unmated ------ Passed Thermal Mated------Passed Unmated ------ Passed 0 Humidity Mated ----- Passed Unmated ----- 6853Meg Ω ----- Passed

RESULTS Continued

			RESULTS Continued	
Do	w1 to Ro	xw1		
		W1		
•	Initial	Motod	10000Meg Ω	Doggad
	0		10000Meg Ω	
•	Therm	_	100001v1eg 32	1 asseu
•	O		10000Meg Ω	Passad
	0		10000Meg Ω	
•	Humid		100001106 82	I assed
·	O	·	5391Meg Ω	Passed
	0		\sim 6259Meg Ω	
	Ü		vzezinieg uz	I dissou
Ro	w2 to Ro	ow2		
•	Initial			
	0	Mated	10000Meg Ω	Passed
	0		10000Meg Ω	
•	Therm	al	_	
	0	Mated	10000Meg Ω	Passed
	0	Unmated	10000Meg Ω	Passed
•	Humid	ity		
	0	Mated	5981Meg Ω	Passed
	0	Unmated	6397Meg $Ω$	Passed
Dieles	twia II/	thatandina Valtaga mini	muma DWW	
Dielec	ctric vvi	thstanding Voltage mini	mums, Dvv v	
•	Minim	ums		
	0	Breakdown Voltage	1125 VAC	
	0	Test Voltage	844 VAC	
	0	Working Voltage	281 VAC	
Pin to	Din			
•		DWV	Doccod	
•		al DWV		
•		ity DWV		
•	Hulliu	ity Dvv v	asseu	
Pin to	Power			
•	Initial 1	DWV	Passed	
•	Therm	al DWV	Passed	
•	Humid	ity DWV	Passed	
Down	to Powe	1 4		
1 OWEI		1 DWV	Daggad	
_		al DWV		
•				
•	Humid	ity DWV	Passed	
Row1	to Row1			
•	Initial 1	DWV	Passed	
•	Therm	al DWV	Passed	
•		ity DWV		
D 4				
	to Row2		- -	
•		DWV		
•		al DWV		
•	Humid	ity DWV	Passed	

Part description: ET60S/ET60T

RESULTS Continued

LLCR Gas Tight (144 signal and 48 power LLCR test points)

Power pin

- Initial ------0,26mOhms Max
- Gas-Tight

0	<= +5.0 mOhms	48 Points	Stable
-		0 Points	2000000
-		0 Points	
		0 Points	-
		0 Points	O
		0 Points	

+15.1 to +50.0 mOhms ------ O Points ----- Marginal
 +50.1 to +2000 mOhms ----- Unstable
 >+2000 mOhms ---- O Points ---- O Points ---- Open Failure

LLCR Thermal Aging (144 signal and 48 power LLCR test points)

Signal pin

- Initial ------ 16.74mOhms Max
- Thermal Aging

0	<= +5.0 mOhms	144 Points	Stable
0	+5.1 to +10.0 mOhms	0 Points	Minor
0	+10.1 to +15.0 mOhms	0 Points	Acceptable
0	+15.1 to +50.0 mOhms	0 Points	Marginal
0	+50.1 to +2000 mOhms	0 Points	Unstable
0	>+2000 mOhms	0 Points	Open Failure

Power pin

- Initial ------0,23mOhms Max
- Thermal Aging

0	<= +5.0 mOhms	48 Points	Stable
		0 Points	
0	+10.1 to +15.0 mOhms	0 Points	Acceptable
		0 Points	-
		0 Points	U
		0 Points	

RESULTS Continued

$\mathbf{L}\mathbf{L}$

Initial		16 86mOhms May	
	ility, 100 Cycles	10.00mOmms 141ax	
Ourab	<= +5.0 mOhms	144 Points	Stable
0	+5.1 to +10.0 mOhms		
0	+10.1 to +15.0 mOhms		
0	+15.1 to +50.0 mOhms		•
0	+50.1 to +2000 mOhms		O
0	>+2000 mOhms		
Therm		onts	open ranu
	<= +5.0 mOhms	1// Doints	Stable
0	+5.1 to +10.0 mOhms		
0	+10.1 to +15.0 mOhms		
0	+15.1 to +50.0 mOhms		_
0	+50.1 to +2000 mOhms		
0	>+2000 mOhms		
0		Points	Орен ғани
Humid		144 D. S. 4	C4-1-1-
0	<= +5.0 mOhms		
0	+5.1 to +10.0 mOhms		
0	+10.1 to +15.0 mOhms		_
0	+15.1 to +50.0 mOhms		0
0	+50.1 to +2000 mOhms		
0	>+2000 mOhms	Points	Open Fanu
wer pin			
Initial -		0.26mOhms Max	
Durab	ility, 100 Cycles		
0	<= +5.0 mOhms	48 Points	Stable
0	+5.1 to +10.0 mOhms		
0	+10.1 to +15.0 mOhms		
0	+15.1 to +50.0 mOhms		-
0	+50.1 to +2000 mOhms		
0	>+2000 mOhms		
			~ P
	nal		
Therm		48 Points	Stable
Therm	<= +5.0 mOhms		
Therm o o	<= +5.0 mOhms+5.1 to +10.0 mOhms	0 Points	Minor
Therm o o	<= +5.0 mOhms +5.1 to +10.0 mOhms	0 Points 0 Points	Minor Acceptable
Therm o o o	<= +5.0 mOhms +5.1 to +10.0 mOhms	0 Points 0 Points 0 Points	Minor Acceptable Marginal
Therm	<= +5.0 mOhms +5.1 to +10.0 mOhms	0 Points0 Points0 Points0 Points0 Points	Minor Acceptable Marginal Unstable
Therm	<= +5.0 mOhms	0 Points0 Points0 Points0 Points0 Points	Minor Acceptable Marginal Unstable
Therm o o o o Humid	<= +5.0 mOhms	0 Points0 Points0 Points0 Points0 Points0 Points	Minor Acceptable Marginal Unstable Open Failu
Therm o o o o Humid	<= +5.0 mOhms		Minor Acceptable Marginal Unstable Open Failu
Therm	<= +5.0 mOhms		Minor Acceptable Marginal Unstable Open Failu Stable
Therm	<= +5.0 mOhms		Minor Acceptable Marginal Unstable Open Failu Stable Minor Acceptable
Therm	<= +5.0 mOhms		Minor Acceptable Marginal Unstable Open Failu Stable Minor Acceptable

RESULTS Continued

LLCR Shock & Vibration (144 signal and 48 power LLCR test points) Signal pin Initial ----- 18.62mOhms Max Shock & Vibration <= +5.0 mOhms------ Stable +5.1 to +10.0 mOhms ------ Minor +10.1 to +15.0 mOhms ------ Acceptable +15.1 to +50.0 mOhms ------ Marginal +50.1 to +2000 mOhms------ Unstable >+2000 mOhms------ Open Failure Power pin Initial ------0.29mOhms Max **Shock & Vibration** <= +5.0 mOhms------ 48 Points ----- Stable +5.1 to +10.0 mOhms ----- Minor +10.1 to +15.0 mOhms ------ Acceptable +15.1 to +50.0 mOhms ------ Marginal +50.1 to +2000 mOhms------ Unstable >+2000 mOhms------ Open Failure **Mechanical Shock & Random Vibration:** Shock No Damage------Pass 50 Nanoseconds ------ Pass Vibration

- No Damage------Pass
- 50 Nanoseconds ------ Pass

Tracking Code: 220319_Report_Rev_2	Part #: ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP
Part description: ET60S/ET60T	

DATA SUMMARIES

TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
- 2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
- 3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1° C (computer-controlled data acquisition).
- 4) Adjacent contacts were powered:

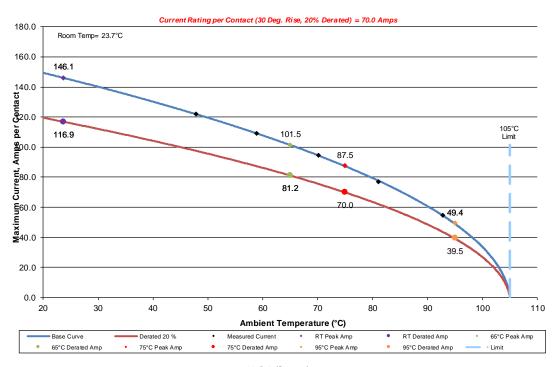
DATA SUMMARIES CONTINUED

Power Pins

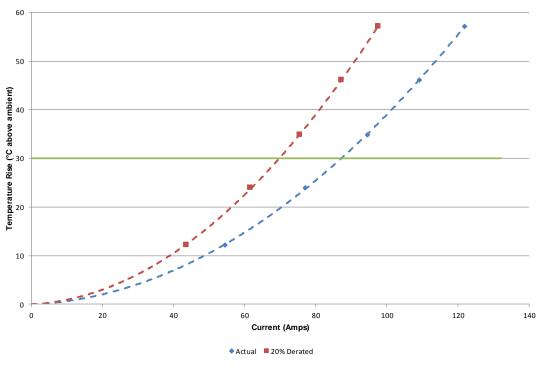
Tracking Code: 220319_Report_Rev_2

a. Linear configuration with 1 adjacent power conductors/contacts powered

227578 (Samtec) 1 (1x1-Power Pins) Contacts in Series Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



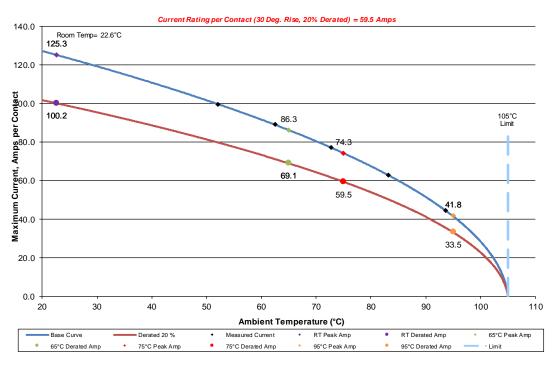
227578 (Samtec)
1 (1x1-Power Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



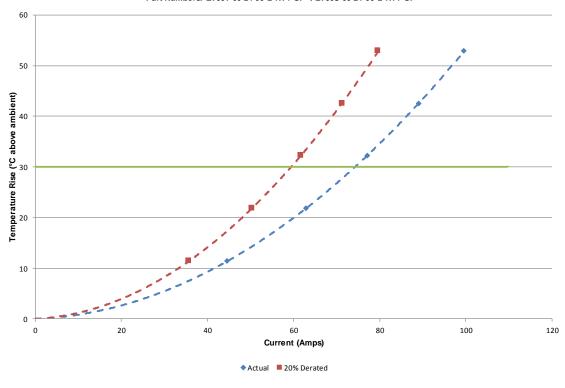
DATA SUMMARIES Continued

b. Linear configuration with 2 adjacent power conductors/contacts powered

227578 (Samtec)
2 (1x2-Power Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



227578 (Samtec)
2 (1x2-Power Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP

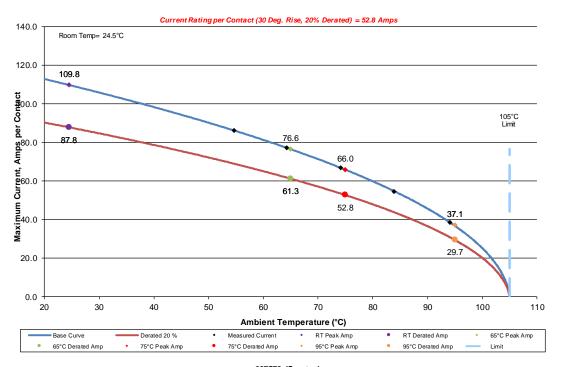


Part description: ET60S/ET60T

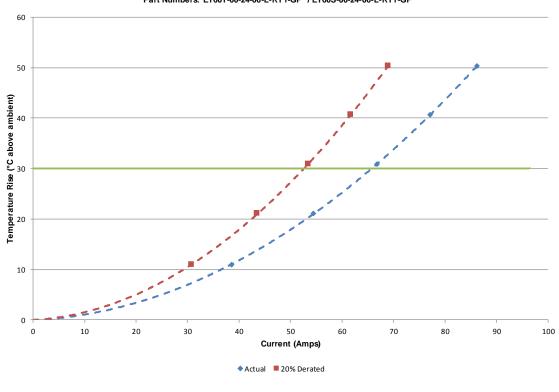
DATA SUMMARIES Continued

c. Linear configuration with 3 adjacent power conductors/contacts powered

227578 (Samtec) 3 (1x3-Power Pins) Contacts in Series Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



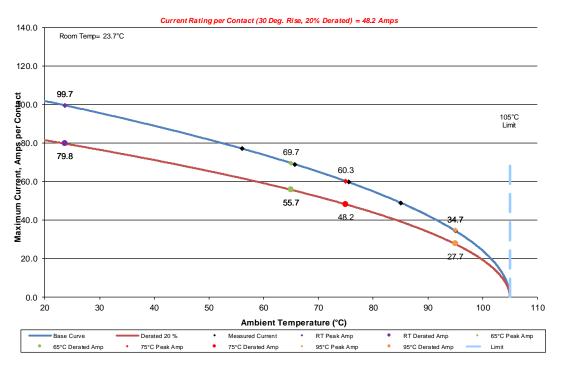
227578 (Samtec)
3 (1x3-Power Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



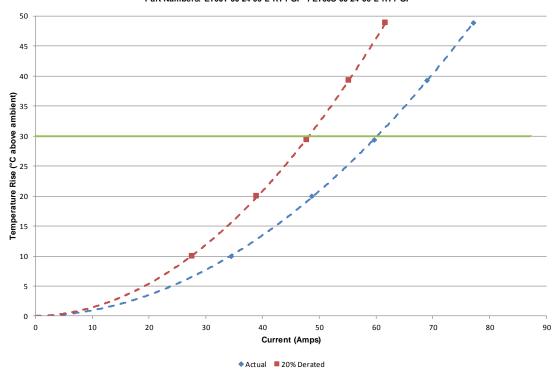
DATA SUMMARIES Continued

d. Linear configuration with 4 adjacent power conductors/contacts powered

227578 (Samtec)
4 (1x4-Power Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



227578 (Samtec) 4 (1x4-Power Pins) Contacts in Series Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP

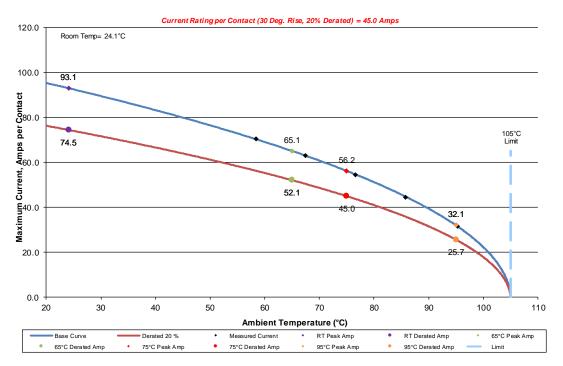


Part description: ET60S/ET60T

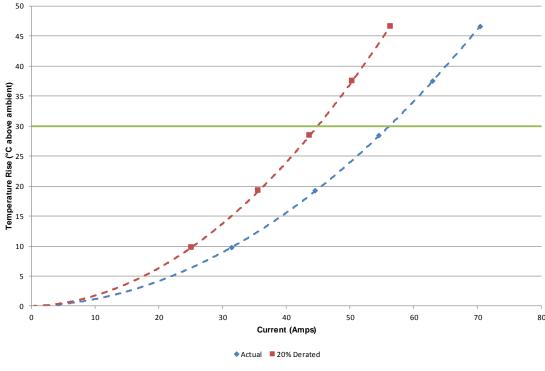
DATA SUMMARIES Continued

e. Linear configuration with all adjacent power conductors/contacts powered

227578 (Samtec)
6 (All Power-Power Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



227578 (Samtec)
6 (All Power-Power Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



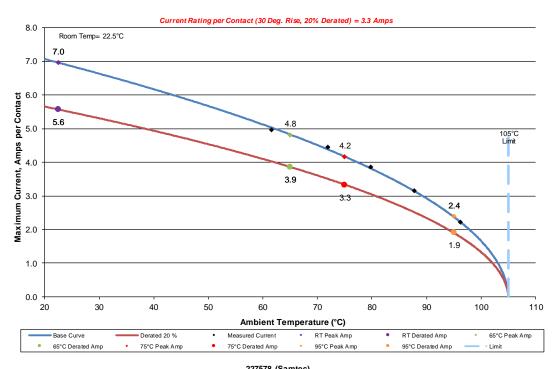
DATA SUMMARIES Continued

Signal Pins

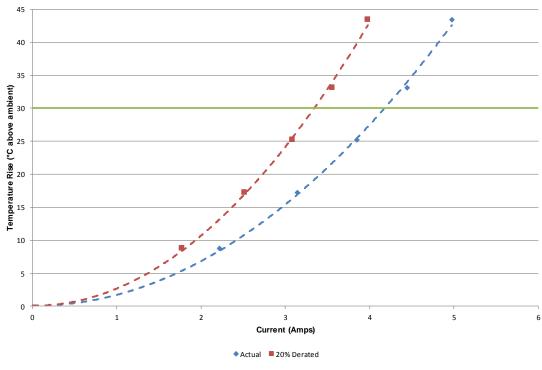
Tracking Code: 220319_Report_Rev_2

f. Linear configuration with 3 adjacent signal conductors/contacts powered

227578 (Samtec)
3 (3x1-Signal Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



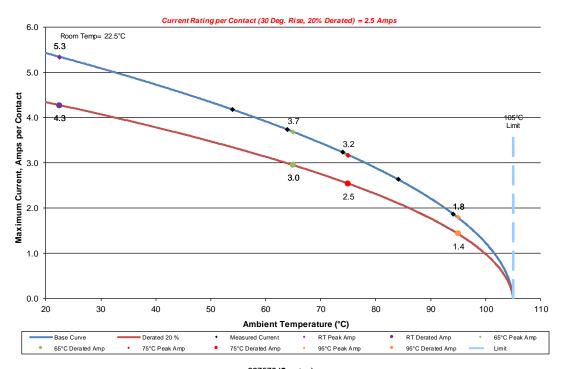
227578 (Samtec) 3 (3x1-Signal Pins) Contacts in Series Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



DATA SUMMARIES Continued

g. Linear configuration with 6 adjacent signal conductors/contacts powered

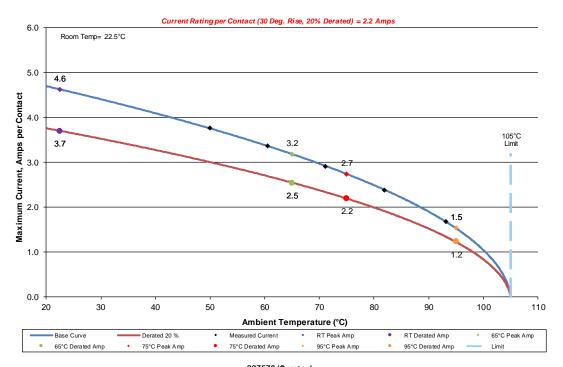
227578 (Samtec)
6 (3x2-Signal Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



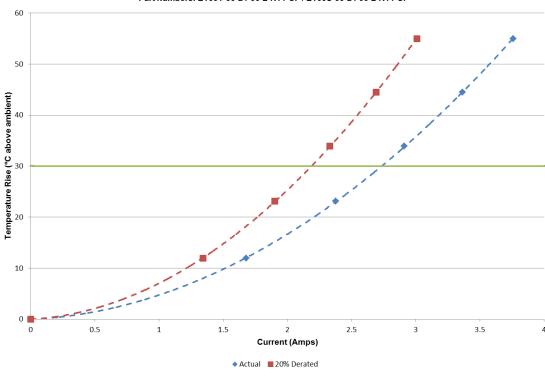
DATA SUMMARIES Continued

h. Linear configuration with 9 adjacent signal conductors/contacts powered

227578 (Samtec) 9 (3x3-Signal Pins) Contacts in Series Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



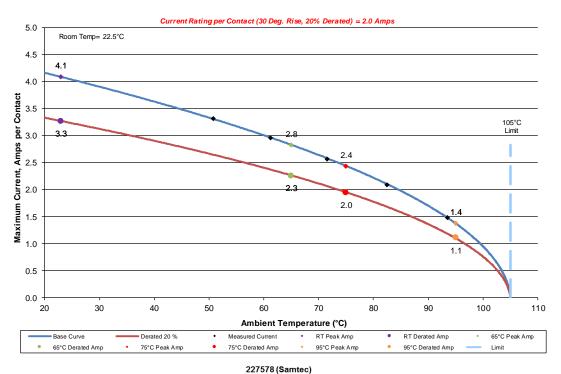
227578 (Samtec) 9 (3x3-Signal Pins) Contacts in Series Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP

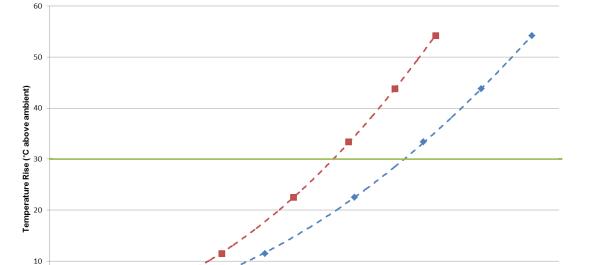


DATA SUMMARIES Continued

i. Linear configuration with 12 adjacent signal conductors/contacts powered

227578 (Samtec)
12 (3x4-Signal Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP





12 (3x4-Signal Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP

Current (Amps)

◆ Actual ■ 20% Derated

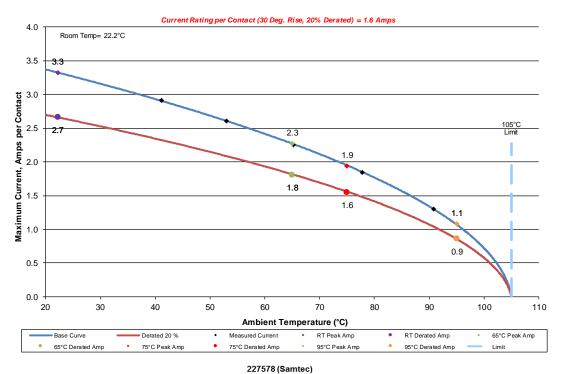
0

0.5

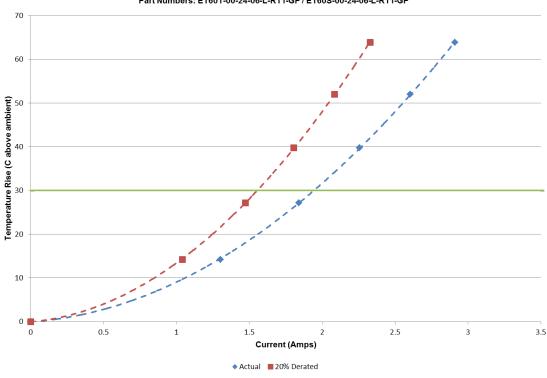
DATA SUMMARIES Continued

j. Linear configuration with all adjacent signal conductors/contacts powered

227578 (Samtec)
24 (All Power-Signal Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



24 (All Power - Signal Pins) Contacts in Series
Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



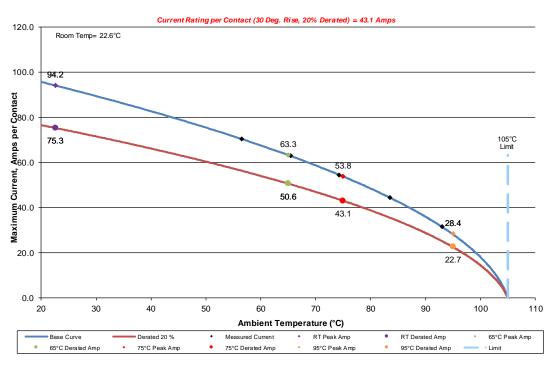
Part description: ET60S/ET60T

DATA SUMMARIES Continued

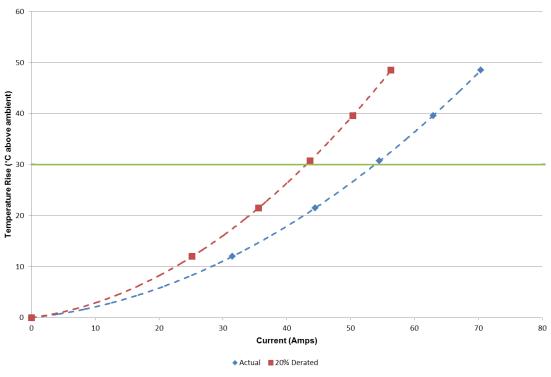
k. Linear configuration with all adjacent signal conductors and power conductors/contacts powered

227578 (Samtec)(Signal Pins Powered @ 1/2 rated current @ .95 AMPS)

6 (All Power-Power Pins) Contacts in Series



227578 (Samtec)(Signal Pins Powered @ 1/2 rated current ,0.95 Amps) 6 (All Power-Power Pins) Contacts in Series Part Numbers: ET60T-00-24-06-L-RT1-GP / ET60S-00-24-06-L-RT1-GP



Tracking Code: 220319_Report_Rev_2 Part #: ET60T-00-2
Part description: ET60S/ET60T

DATA SUMMARIES Continued

Mating\Unmating Force: Mating\Unmating Durability Group

		Ini	tial			After 25	Cycles	
	Mat	ting	Unm	ating	Mat	ting	Unm	ating
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	26.38	5.93	22.15	4.98	32.25	7.25	25.71	5.78
Maximum	34.25	7.70	26.91	6.05	38.74	8.71	31.89	7.17
Average	29.15	6.55	24.34	5.47	35.39	7.96	28.38	6.38
St Dev	2.70	0.61	1.58	0.36	1.90	0.43	1.98	0.45
Count	8	8	8	8	8	8	8	8
		After 50) Cycles			After 75	Cycles	
	Mat	ting	Unm	ating	Mat	ting	Unm	ating
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	36.96	8.31	27.98	6.29	39.94	8.98	31.80	7.15
Maximum	42.61	9.58	35.45	7.97	48.66	10.94	39.72	8.93
Average	39.53	8.89	31.67	7.12	44.39	9.98	36.01	8.10
St Dev	1.99	0.45	2.53	0.57	3.88	0.87	2.81	0.63
Count	8	8	8	8	8	8	8	8
		After 10	0 Cycles			After H	umidity	
	Mat	ting	Unm	ating	Mat	ting	Unm	ating
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	44.17	9.93	37.14	8.35	21.48	4.83	16.28	3.66
Maximum	54.75	12.31	44.30	9.96	27.80	6.25	22.33	5.02
Average	50.07	11.26	40.58	9.12	24.44	5.50	18.92	4.25
St Dev	4.27	0.96	2.20	0.49	2.25	0.51	1.77	0.40
Count	8	8	8	8	8	8	8	8

Mating\Unmating Force: Thermal Aging Group

		Ini	tial		After Thermals						
	Mat	ing	Unm	ating	Mat	ing	Unm	ating			
	Newtons Force (Lbs)		Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)			
Minimum	29.00	6.52	23.71	5.33	20.59	4.63	14.72	3.31			
Maximum	48.84	10.98	27.13	6.10	22.60	5.08	18.06	4.06			
Average	37.46	8.42	25.45	5.72	21.30	4.79	16.21	3.65			
St Dev	7.53	1.69	1.21	0.27	0.67	0.15	1.12	0.25			
Count	8	8	8	8	8	8	8	8			

Tracking Code: 220319_Report_Rev_2	Part #: ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP
Part des	scription: ET60S/ET60T

NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) For Normal force 8-10 measurements are taken and the averages reported.

Power pin left

Initial		Deflections in inches Forces in Grams													
IIIItiai	0.0013	0.0026	0.0040	0.0053	0.0066	0.0079	0.0091	0.0106	0.0119	0.0132	SET				
Averages	41.67	88.11	134.88	181.88	232.18	280.66	324.73	374.66	422.39	470.93	0.0008				
Min	28.20	65.20	108.40	156.70	204.20	248.60	289.50	343.20	394.10	442.10	0.0005				
Max	55.20	107.00	153.80	205.30	257.60	310.10	358.20	407.00	456.50	503.90	0.0016				
St. Dev	10.198	13.010	14.602	16.354	16.996	18.865	20.032	19.727	19.468	19.387	0.0003				
Count	12	12	12	12	12	12	12	12	12	12	12				

After		Deflections in inches Forces in Grams												
Thermals	0.0013	0.0026	0.0040	0.0053	0.0066	0.0079	0.0091	0.0106	0.0119	0.0132	SET			
Averages	-0.08	-0.08	-0.08	16.05	56.91	103.25	141.74	194.86	242.13	289.43	0.0048			
Min	-0.40	-0.40	-0.40	0.10	34.00	81.50	124.20	173.80	218.20	264.60	0.0043			
Max	0.10	0.10	0.10	28.30	76.20	119.30	169.40	229.70	281.40	334.20	0.0053			
St. Dev	0.148	0.171	0.176	10.382	13.413	13.648	13.995	16.972	18.018	19.659	0.0003			
Count	12	12	12	12	12	12	12	12	12	12	12			

Power pin middle

	piii iiiiaai														
Initial		Deflections in inches Forces in Grams													
Illitial	0.0013	0.0026	0.0040	0.0053	0.0066	0.0079	0.0091	<u>0.0106</u>	<u>0.0119</u>	0.0132	SET				
Averages	40.68	80.85	124.38	171.04	222.00	269.61	313.03	363.58	408.03	457.68	0.0003				
Min	24.10	56.50	98.90	134.20	183.60	227.30	273.70	323.60	371.20	420.80	0.0001				
Max	54.20	102.20	151.60	202.90	254.10	303.20	347.20	402.60	448.10	498.90	0.0005				
St. Dev	9.804	15.789	16.277	18.908	18.432	19.529	18.984	20.245	20.462	20.363	0.0001				
Count	12	12	12	12	12	12	12	12	12	12	12				

After		Deflections in inches Forces in Grams													
Thermals	0.0013	0.0026	0.0040	0.0053	0.0066	0.0079	0.0091	0.0105	0.0119	0.0132	SET				
Averages	0.03	0.03	0.04	10.53	49.93	95.61	132.81	186.04	231.06	277.24	0.0050				
Min	-0.40	-0.40	-0.40	0.10	33.50	75.80	116.80	168.10	210.80	252.70	0.0045				
Max	0.40	0.40	0.40	23.80	65.20	115.10	153.20	208.20	253.60	297.60	0.0055				
St. Dev	0.314	0.314	0.318	9.135	11.273	13.416	12.461	12.998	13.503	13.736	0.0004				
Count	12	12	12	12	12	12	12	12	12	12	12				

Tracking Code: 220319_Report_Rev_2	Part #: ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP
Part de	scription: FT60S/FT60T

Power pin right

T., :4: -1				Def	lections in	inches Fo	rces in Gra	ıms			
Initial	0.0013	0.0026	0.0040	0.0053	0.0066	0.0079	0.0091	0.0106	0.0119	0.0132	SET
Averages	36.82	69.73	109.51	153.36	201.33	247.43	289.25	336.86	380.22	425.78	0.0002
Min	22.80	50.10	87.80	125.60	170.50	217.70	260.10	310.60	353.70	401.00	0.0000
Max	53.50	98.20	140.80	190.30	243.30	286.40	331.20	381.80	423.00	472.50	0.0004
St. Dev	8.928	14.084	15.450	15.996	18.233	17.295	18.052	18.181	17.335	17.935	0.0001
Count	12	12	12	12	12	12	12	12	12	12	12

After		Deflections in inches Forces in Grams													
Thermals	0.0013	0.0026	0.0040	0.0053	0.0066	0.0079	0.0091	<u>0.0105</u>	<u>0.0119</u>	0.0132	SET				
Averages	-0.08	-0.08	-0.09	16.72	56.76	100.47	135.74	184.26	225.75	267.83	0.0047				
Min	-0.40	-0.40	-0.40	0.10	41.20	85.50	121.30	172.70	212.70	252.20	0.0041				
Max	0.20	0.20	0.10	31.60	75.00	118.80	157.30	207.70	251.70	295.10	0.0051				
St. Dev	0.175	0.159	0.144	8.685	8.635	8.709	9.198	10.250	11.438	12.893	0.0003				
Count	12	12	12	12	12	12	12	12	12	12	12				

NORMAL FORCE (FOR CONTACTS TESTED OUTSIDE THE HOUSING):

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) Typically, 8-10 readings are taken and the averages reported.

Signal pin row1 left

Digital	PIHIOWI	1010													
T., :4: -1		Deflections in inches Forces in Grams													
Initial	0.0009	0.0018	0.0027	0.0040	0.0045	0.0054	0.0063	0.0072	0.0081	0.0090	SET				
Averages	13.54	26.05	36.53	56.00	63.43	74.13	86.21	99.74	111.98	123.45	0.0002				
Min	12.20	22.00	31.20	47.60	53.60	63.60	75.30	86.90	98.50	110.20	0.0000				
Max	15.40	29.40	40.40	61.30	67.90	80.80	94.80	108.70	121.30	133.60	0.0005				
St. Dev	1.054	2.280	2.811	4.380	4.481	5.418	5.681	6.674	7.585	8.254	0.0001				
Count	12	12	12	12	12	12	12	12	12	12	12				

After		Deflections in inches Forces in Grams													
Thermals	0.0009	0.0018	0.0027	0.0040	0.0045	0.0054	0.0063	0.0072	0.0081	<u>0.0090</u>	SET				
Averages	3.43	16.12	27.78	48.28	55.64	67.06	81.05	95.52	108.02	121.13	0.0010				
Min	-0.20	11.80	22.90	43.60	49.30	60.00	73.60	86.40	97.90	109.40	0.0005				
Max	7.80	20.00	31.80	53.40	61.60	71.30	86.60	102.20	115.30	129.00	0.0016				
St. Dev	2.928	3.018	3.158	3.626	4.345	3.798	3.925	4.691	5.390	6.027	0.0003				
Count	12	12	12	12	12	12	12	12	12	12	12				

Tracking Code: 220319_Report_Rev_2	Part #: ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP
Part des	ecription: FT60S/FT60T

Signal pin row1 right

Initial		Deflections in inches Forces in Grams													
IIIItiai	<u>0.0009</u>	0.0018	0.0027	<u>0.0040</u>	<u>0.0045</u>	0.0054	0.0063	0.0072	0.0081	0.0090	SET				
Averages	12.98	24.75	35.09	54.32	61.58	72.18	84.40	97.75	109.44	121.10	0.0003				
Min	11.80	22.80	32.80	50.60	55.70	66.00	76.40	87.70	99.10	110.40	0.0001				
Max	14.40	28.20	39.10	60.20	67.70	80.50	94.40	108.50	122.10	134.40	0.0004				
St. Dev	0.887	1.798	1.687	2.758	3.326	4.073	4.513	5.104	5.776	6.070	0.0001				
Count	12	12	12	12	12	12	12	12	12	12	12				

After		Deflections in inches Forces in Grams													
Thermals	0.0009	0.0018	0.0027	0.0040	0.0045	0.0054	0.0063	0.0072	0.0081	0.0090	SET				
Averages	2.51	14.58	25.67	45.89	52.35	63.88	76.73	90.53	103.03	115.48	0.0011				
Min	-0.30	9.40	20.20	40.50	45.40	57.00	67.80	81.50	93.90	104.00	0.0008				
Max	8.50	18.40	31.20	53.00	60.50	73.80	88.10	104.60	118.30	131.90	0.0020				
St. Dev	2.859	2.906	3.594	3.837	4.603	4.857	5.641	6.559	6.879	7.527	0.0003				
Count	12	12	12	12	12	12	12	12	12	12	12				

Signal pin row2 left

Initial	-	Deflections in inches Forces in Grams													
IIIItiai	0.0009	0.0018	0.0027	0.0040	0.0045	0.0054	0.0063	0.0072	0.0081	0.0090	SET				
Averages	12.77	24.58	35.79	55.90	63.22	74.17	86.78	100.83	113.36	125.12	0.0002				
Min	11.20	22.20	32.50	50.10	56.30	67.40	79.10	92.30	103.60	115.50	0.0001				
Max	15.80	27.70	38.70	62.00	69.50	81.50	94.70	107.90	120.60	131.90	0.0003				
St. Dev	1.221	1.750	1.924	3.119	3.450	3.976	4.484	4.486	5.106	5.288	0.0001				
Count	12	12	12	12	12	12	12	12	12	12	12				

After		Deflections in inches Forces in Grams									
Thermals	0.0009	0.0018	0.0027	0.0040	0.0045	0.0054	0.0063	0.0072	0.0081	0.0090	SET
Averages	3.74	15.73	26.84	46.29	53.55	64.59	77.20	91.49	104.93	117.43	0.0009
Min	-0.10	9.30	20.40	40.00	45.50	55.80	66.70	79.20	93.20	103.90	0.0006
Max	9.80	22.20	34.00	52.80	62.00	73.30	87.90	103.60	117.10	130.50	0.0012
St. Dev	3.192	3.844	4.039	4.853	6.280	6.185	7.399	8.369	8.330	8.647	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12

Signal pin row2 right

Initial		Deflections in inches Forces in Grams													
Illitial	0.0009	0.0018	0.0027	0.0040	0.0045	<u>0.0054</u>	0.0063	0.0072	0.0081	0.0090	SET				
Averages	11.88	23.37	34.12	53.23	59.99	70.13	81.80	95.08	106.12	117.70	0.0003				
Min	10.20	20.70	29.30	49.20	55.10	63.90	76.00	86.90	99.70	111.70	0.0001				
Max	13.90	27.40	39.50	62.30	69.00	79.80	90.20	105.70	116.50	127.80	0.0004				
St. Dev	1.054	2.021	2.622	3.546	3.893	4.486	4.365	5.415	5.402	5.149	0.0001				
Count	12	12	12	12	12	12	12	12	12	12	12				

After	Deflections in inches Forces in Grams										
Thermals	0.0009	0.0018	0.0027	0.0040	0.0045	0.0054	0.0063	0.0072	0.0081	0.0090	SET
Averages	2.35	14.59	25.27	44.13	50.15	61.44	72.72	85.93	97.52	108.55	0.0012
Min	-0.10	10.20	19.10	39.10	45.50	56.30	66.40	79.60	89.50	100.00	0.0007
Max	5.00	17.70	29.60	50.20	55.40	68.40	80.80	95.80	108.80	118.80	0.0018
St. Dev	1.955	2.509	3.268	3.468	3.330	3.860	4.631	5.575	5.935	6.761	0.0004
Count	12	12	12	12	12	12	12	12	12	12	12

Tracking Code: 220319_Report_Rev_2	Part #: ET60T-00-24-06-L-RT1-GP/ET60S-00-24-06-L-RT1-GP
Part des	scription: ET60S/ET60T

Signal pin row3 left

In:id: a1	_	Deflections in inches Forces in Grams													
Initial	0.0009	0.0018	0.0027	0.0040	0.0045	0.0054	0.0063	0.0072	0.0081	0.0090	SET				
Averages	13.35	26.35	37.28	57.46	65.03	76.28	88.52	101.75	113.98	125.80	0.0002				
Min	12.00	23.30	33.60	49.60	56.10	66.40	77.90	88.60	99.70	111.20	0.0000				
Max	16.30	29.90	44.00	64.10	71.60	84.00	95.10	108.70	121.20	134.40	0.0003				
St. Dev	1.146	1.939	2.711	4.251	4.407	5.415	5.782	6.909	7.495	7.890	0.0001				
Count	12	12	12	12	12	12	12	12	12	12	12				

After		Deflections in inches Forces in Grams									
Thermals	0.0009	0.0018	0.0027	0.0040	0.0045	0.0054	0.0063	0.0072	0.0081	0.0090	SET
Averages	2.07	14.90	26.44	46.26	52.85	64.77	78.29	93.45	106.38	119.05	0.0010
Min	-0.10	11.20	22.50	39.80	45.80	56.80	68.30	83.00	96.10	109.40	0.0007
Max	7.70	19.00	30.50	51.10	58.70	70.20	83.40	99.40	112.70	124.90	0.0012
St. Dev	2.374	2.656	2.625	3.140	3.262	3.426	3.900	4.458	4.636	4.205	0.0002
Count	12	12	12	12	12	12	12	12	12	12	12

Signal pin row3 right

Initial		Deflections in inches Forces in Grams													
Illitiai	0.0009	0.0018	0.0027	0.0040	0.0045	0.0054	0.0063	0.0072	0.0081	0.0090	SET				
Averages	12.10	23.35	33.69	52.48	59.59	69.54	81.58	94.51	105.62	116.98	0.0004				
Min	11.00	21.10	31.50	48.30	54.70	64.40	76.30	86.30	98.10	110.00	0.0002				
Max	13.50	26.30	36.10	55.30	63.30	74.10	87.00	100.20	112.70	122.70	0.0007				
St. Dev	0.716	1.623	1.368	2.102	2.831	3.115	3.397	3.815	4.350	4.084	0.0002				
Count	12	12	12	12	12	12	12	12	12	12	12				

After		Deflections in inches Forces in Grams									
Thermals	0.0009	0.0018	0.0027	0.0040	0.0045	0.0054	0.0063	0.0072	0.0081	0.0090	SET
Averages	1.90	13.08	23.68	42.57	49.68	61.10	72.91	86.38	98.88	111.42	0.0011
Min	-0.40	9.00	18.80	35.00	43.00	53.70	65.20	78.20	91.20	102.00	0.0007
Max	8.40	19.50	30.70	52.60	60.50	72.90	86.60	101.80	114.60	128.00	0.0015
St. Dev	3.221	3.795	4.175	4.703	4.632	4.937	5.804	5.904	5.966	6.595	0.0003
Count	12	12	12	12	12	12	12	12	12	12	12

Part description: ET60S/ET60T

DATA SUMMARIES Continued

INSULATION RESISTANCE (IR):

Tracking Code: 220319_Report_Rev_2

	Pin to Pin				
_	Mated Unmated Unmated				
Minimum	ET60S/ET60T	ET60S	ET60T		
Initial	10000	10000	10000		
Thermal	10000	10000	10000		
Humidity	5687	6581	6423		

_	Mated	Unmated	Unmated	
Minimum	ET60S/ET60T	ET60S	ET60T	
Initial	10000	10000	10000	
Thermal	10000	10000	10000	
Humidity	5391	6259	6392	
_				
	Power to Power			

Row1 to Row1

	Pin to Power				
	Mated Unmated Unmated				
Minimum	ET60S/ET60T	ET60S	ET60T		
Initial	10000	10000	10000		
Thermal	10000	10000	10000		
Humidity	10000	10000	10000		

	Power to Power				
_	Mated Unmated Unmated				
Minimum	ET60S/ET60T	ET60S	ET60T		
Initial	10000	10000	10000		
Thermal	10000 10000		10000		
Humidity	5943	6853	7069		

	Row2to Row2				
	Mated Unmated Unmated				
Minimum	ET60S/ET60T	ET60S	ET60T		
Initial	10000	10000	10000		
Thermal	10000	10000	10000		
Humidity	5981	6397	7284		

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

Voltage Rating Summary		
Minimum ET60S/ET60T		
Break Down Voltage	1125	
Test Voltage	844	
Working Voltage	281	

Pin to Pin		
Initial Test Voltage Passed		
After Thermal Test Voltage	Passed	
After Humidity Test Voltage	Passed	

Row to Row		
Initial Test Voltage Passed		
After Thermal Test Voltage	Passed	
After Humidity Test Voltage	Passed	

Pin to Ground			
Initial Test Voltage Passed			
After Thermal Test Voltage	Passed		
After Humidity Test Voltage	Passed		

Pin to Closest Metallic Hardware		
Initial Test Voltage Passed		
After Thermal Test Voltage Passed		
After Humidity Test Voltage	Passed	

Ground to Closest Metallic Hardware		
Initial Test Voltage Passed		
After Thermal Test Voltage	Passed	
After Humidity Test Voltage	Passed	

Part description: ET60S/ET60T

DATA SUMMARIES Continued

LLCR Durability:

- 1) A total of 144 signal points and 48 power points were measured.
- 2) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. <= +5.0 mOhms:-----Stable
 - b. +5.1 to +10.0 mOhms: ------Minor
 - c. +10.1 to +15.0 mOhms: ------Acceptable
 - d. +15.1 to +50.0 mOhms: ------Marginal
 - e. +50.1 to +2000 mOhms ------Unstable
 - f. >+2000 mOhms: -----Open Failure

	LLCR Measurement Summaries by Pin Type			
Date	10/22/2012	10/27/2012	11/6/2012	11/17/2012
Room Temp (Deg C)	24	24	24	22
Rel Humidity (%)	52	52	52	56
Technician	Kason He	Kason He	Kason He	Kason He
mOhm values	Actual	Delta	Delta	Delta
		100		
	Initial	Cycles	Therm Shck	Humidity
		Pin Type	1: Signal	
Average	14.20	0.20	0.21	0.38
St. Dev.	1.91	0.27	0.28	0.34
Min	10.34	0.00	0.00	0.01
Max	16.86	1.81	1.69	2.89
Summary Count	144	144	144	144
Total Count	144	144	144	144
	Pin Type 2: Power			
Average	0.22	0.01	0.02	0.02
St. Dev.	0.01	0.01	0.01	0.01
Min	0.21	0.00	0.00	0.00
Max	0.26	0.06	0.04	0.06
Summary Count	48	48	48	48
Total Count	48	48	48	48

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	<=5	>5 & <=10	>10 & <=15	>15 & <=50	>50 & <=1000	>1000
100 Cycles	192	0	0	0	0	0
Therm Shck	192	0	0	0	0	0
Humidity	192	0	0	0	0	0

Part description: ET60S/ET60T

DATA SUMMARIES Continued

LLCR Thermal Aging:

- 1) A total of 144 signal points and 48 power points were measured.
- 2) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 3) A computer program, LLCR 221.exe, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.

	LLCR Measurement Summaries by Pin Type			
Date	10/25/2012	11/6/2012		
Room Temp (Deg C)	24	24		
Rel Humidity (%)	55	52		
Technician	Kason He	Kason He		
mOhm values	Actual	Delta		
	Initial	Thermal		
	Pin Type	1: Signal		
Average	14.07	0.22		
St. Dev.	1.93	0.27		
Min	9.99	0.00		
Max	16.74	1.35		
Summary Count	144	144		
Total Count	144	144		
	Pin Type	2: Power		
Average	0.20	0.02		
St. Dev.	0.02	0.02		
Min	0.15	0.00		
Max	0.23	0.12		
Summary Count	48	48		
Total Count	48	48		

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	<=5	>5 & <=10	>10 & <=15	>15 & <=50	>50 & <=1000	>1000
Thermal	192	0	0	0	0	0

Part description: ET60S/ET60T

DATA SUMMARIES Continued

LLCR Gas Tight:

- 1) A total of 144 signal points and 48 power points were measured.
- 2) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. <= +5.0 mOhms: ------Stable b. +5.1 to +10.0 mOhms: ------Minor c. +10.1 to +15.0 mOhms: -------Acceptable d. +15.1 to +50.0 mOhms: -------Marginal e. +50.1 to +2000 mOhms: -------Unstable
 - f. >+2000 mOhms:-----Open Failure

	LLCR Measurement Summaries by Pin Type		
Date	10/25/2012	11/23/2012	
Room Temp (Deg C)	24	22	
Rel Humidity (%)	55	58	
Technician	Kason He	Kason He	
mOhm values	Actual	Delta	
	Initial	Acid Vapor	
	Pin Type	1: Signal	
Average	13.68	0.20	
St. Dev.	2.17	0.24	
Min	7.68	0.00	
Max	16.83	1.31	
Summary Count	144	144	
Total Count	144	144	
	Pin Type	2: Power	
Average	0.21	0.03	
St. Dev.	0.02	0.02	
Min	0.17	0.00	
Max	0.26	0.12	
Summary Count	48	48	
Total Count	48	48	

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	<=5	>5 & <=10	>10 & <=15	>15 & <=50	>50 & <=1000	>1000
Acid Vapor	192	0	0	0	0	0

Part description: ET60S/ET60T

DATA SUMMARIES Continued

LLCR Shock &Vibration:

- 1). A total of 144 signal points and 48 power points were measured.
- 2). EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 3). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. <= +5.0 mOhms: -----Stable
 - b. +5.1 to +10.0 mOhms: ------Minor
 - c. +10.1 to +15.0 mOhms: ------Acceptable
 - d. +15.1 to +50.0 mOhms:------Marginal
 - e. +50.1 to +2000 mOhms ------Unstable
 - f. >+2000 mOhms:-----Open Failure

		easurement s by Pin Type
Date	11/2/2012	11/6/2012
Room Temp (Deg C)	21	22
Rel Humidity (%)	34	32
	Tony	Tony
Technician	Wagoner	Wagoner
mOhm values	Actual	Delta
	Initial	Shock-Vib
	Pin Type	e 1: Power
Average	0.24	0.02
St. Dev.	0.02	0.02
Min	0.21	0.00
Max	0.29	0.08
Summary Count	48	48
Total Count	48	48
	Pin Type	e 2: Signal
Average	14.34	0.44
St. Dev.	2.19	0.53
Min	10.11	0.01
Max	18.62	2.78
Summary Count	144	144
Total Count	144	144

LLCR Delta Count by Category						
Stable Minor Acceptable Marginal Unstable Open				Open		
mOhms	<=5	>5 & <=10	>10 & <=15	>15 & <=50	>50 & <=1000	>1000
Shock-Vib	192	0	0	0	0	0

Nanosecond Event Detection:

Shock and Vibration Event Detection Summary				
Contacts tested	60			
Test Condition	C, 100g's, 6ms, Half-Sine			
Shock Events	0			
Test Condition	V-B, 7.56 rms g			
Vibration Events	0			
Total Events	0			

Part description: ET60S/ET60T

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: HZ-TCT-01

Description: Normal force analyzer **Manufacturer:** Mecmesin Multitester **Model:** Mecmesin Multitester 2.5-i

Serial #: 08-1049-04

Accuracy: Last Cal: 4/27/2012, Next Cal: 4/26/2013

Equipment #: HZ-OV-01 Description: Oven Manufacturer: Huida Model: CS101-1E Serial #: CS101-1E-B

Accuracy: Last Cal: 12/13/2012, Next Cal: 12/12/2013

Equipment #: HZ-THC-01

Description: Humidity transmitter

Manufacturer: Thermtron

Model: HMM30C Serial #: D0240037

Accuracy: Last Cal: 3/1/2012, Next Cal: 2/28/2013

Equipment #: HZ-HPM-01 Description: NA9636H Manufacturer: Ainuo

Model: 6031A **Serial #:** 089601091

Accuracy: Last Cal: 3/8/2012, Next Cal: 3/7/2013

Equipment #: MO-04

Description: Multimeter /Data Acquisition System

Manufacturer: Keithley

Model: 2700 **Serial #:** 0798688

Accuracy: Last Cal: 4/20/2012, Next Cal: 4/20/2013

Equipment #: PS-11

Description: Power Supply

Manufacturer: Hewlett Packard / Agilent

Model: AT-6032A **Serial #:** 3440A10457

Accuracy: Last Cal: no calibrate, Next Cal: no calibrate

Equipment #: HZ-MO-05
Description: Micro-ohmmeter
Manufacturer: Keithley

Model: 3706 **Serial #:** 1285188

Accuracy: Last Cal: 11/15/2012, Next Cal: 11/14/2013

Part description: ET60S/ET60T

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: HZ-TSC-01

Description: Vertical Thermal Shock Chamber

Manufacturer: Cincinnatti Sub Zero

Model: VTS-3-6-6-SC/AC Serial #: 10-VT14994 Accuracy: See Manual

... Last Cal: 06/28/2012, Next Cal: 06/27/2013

Equipment #: SVC-01

Description: Shock & Vibration Table

Manufacturer: Data Physics **Model:** LE-DSA-10-20K

Serial #: 10037

Accuracy: See Manual

... Last Cal: 11/30/2012, Next Cal: 11/30/2013

Equipment #: ACLM-01
Description: Accelerometer
Manufacturer: PCB Piezotronics

Model: 352C03 Serial #: 115819 Accuracy: See Manual

... Last Cal: 07/09/2012, Next Cal: 07/09/2013

Equipment #: ED-03

Description: Event Detector **Manufacturer:** Analysis Tech

Model: 32EHD Serial #: 1100604 Accuracy: See Manual

... Last Cal: 06/04/2012, Next Cal: 06/04/2013